



computer tomography
data analysis and visualization
reporting

Description of innovation

Our company facilitates access to non-destructive synchrotron- μ CT analysis at highest sensitivities and spatial resolutions. Bridging the gap between highly advanced laboratory and synchrotron-based analytics and R&D demand, we offer not just consulting services, but a comprehensive all-round package: from sample preparation and the actual measurements over data analysis and visualization to the final reporting. Through us, you gain access to state-of-the-art X-ray sources for highly sensitive assessment of material composition.

We offer

- rapid and smooth access to synchrotron- μ CT analysis
- high sample throughput: hundreds of samples per day
- high resolution: pixel size: 0.2 – 30 μ m
- high energy for dense samples
- phase contrast: for high sensitivity



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